

1 **Resolution Improvement of Differential Phase-Contrast Microscopy via Tilt-Series**
2 **Acquisition for Environmental Cell Application**

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20 **Abstract**

21 A simple method that improves the resolution of the phase measurement of differential phase-
22 contrast (DPC) scanning transmission electron microscopy for closed-type environmental cell
23 applications was developed and tested using a model sample simulating environmental cell
24 observations. Because the top and bottom membranes of an environmental cell are typically
25 far apart, the images from these membranes are shifted widely by tilt-series acquisition, and
26 averaging the images after alignment can effectively eliminate undesired signals from the
27 membranes while improving the signal from the object of interest. It was demonstrated that a
28 phase precision of $2\pi/100$ rad is well achievable using the proposed method for the sample in
29 an environmental cell.

30

31 **Abbreviations**

32 DPC: differential phase-contrast

33 **Introduction**

34 With growing environmental problems, the demand for improving the properties of functional
35 materials is rapidly increasing. For example, catalytic nanoparticles are used for various
36 purposes, such as CO oxidation, NO_x gas purification, selective oxidation, selective
37 hydrogenation, and photocatalytic reactions [1], and improving their performance is strongly
38 desired. Electron microscopy is an ideal method for analyzing these systems, and charge-state
39 characterization correlated with catalytic activity has recently been realized using electron
40 holography [2, 3], showing that the charge amount of nanoparticle catalysis is related to
41 lattice distortion. To further understand the mechanism, it is important to observe these
42 materials under actual operating conditions, such as liquid or gas atmospheres. In such *in situ*
43 observations, closed-type environmental holders that employ electron transparent membranes
44 to confine liquids or gases are widely used [4-8], but high-resolution observation is generally
45 difficult because the contrasts from these membranes are superimposed on the obtained
46 image. For example, Hyllested and Beleggia studied phase measurements using electron
47 holography in gas environmental cell holders and reported a phase resolution of
48 approximately 0.35 rad, stating that the degradation of phase resolution caused by the
49 membrane is more significant than the type and pressure of gas in the environmental cell. [9]
50 Differential phase-contrast (DPC) scanning transmission electron microscopy (STEM) [10,
51 11] measures electronic and/or magnetic fields by measuring the deflection of the transmitted

52 disk. It has been applied to a wide range of materials [12, 13], and in contrast to electron
53 holography, it does not require a reference vacuum area, which is necessary to create an
54 interference pattern with the electron waves that pass through the sample. This is particularly
55 beneficial for the observation of environmental cells in which a reference area is extremely
56 difficult—if not impossible—to obtain.

57 Herein, we propose a simple method that increases the phase measurement precision for an
58 object in a closed-type *in situ* observation holder by averaging tilt-series DPC center of mass
59 (CoM) images. Tilt-series DPC is a well-established technique that was developed to suppress
60 diffraction contrast [14, 15] and extract electric [13] or magnetic [16] information. We used it
61 to discriminate the information of the membranes at different heights from the region of
62 interest.

63 The achievable phase measurement precision [17] is expressed as

$$64 \quad \varphi_{\sigma} = R\sigma_{dCoM} \frac{2\pi}{\lambda}, \quad (1)$$

65 where R represents the spatial resolution, σ_{dCoM} represents the standard deviation of the
66 CoM that corresponds to the precision of the detectable deflection angle, and λ represents
67 the wavelength of incident electrons. The relationship between the electron dose and field
68 resolution [18] is expressed as

$$69 \quad \sigma_{dCoM} = \theta k_0 \left(\frac{1}{2\sqrt{N_e}} \right), \quad (2)$$

70 where θ represents the convergence semi-angle of the probe, k_0 represents the
71 wavenumber, and N_e represents the number of electrons in the diffraction pattern. This is a
72 surprisingly simple function implying that the field resolution is solely dependent on the
73 electron dose and convergence angle and is not dependent on the camera length. This relation
74 was derived under the assumption of static noise, providing the theoretical lower limit of the
75 achievable phase resolution. In the case of the observation using a cell with membranes, the
76 phase noise due to the membrane is superimposed, and those cannot be eliminated even with
77 infinite dose. The objective of this research is to eliminate those with tilt series acquisition. In
78 reality, however, because DPC is a scanning technique, the position of the transmitted disk is
79 also affected by the parallelism of the beam during the scan and how accurately the detector is
80 electro-optically placed in the diffraction plane. Since, the previous studies only confirmed it
81 through numerical simulation [18], we first experimentally verified the precision of the phase
82 measurement (Eq. (2)) by measuring the standard deviation of the CoM as a function of the
83 electron dose. The achievable phase precision was evaluated by assuming a spatial resolution
84 R with the value expected from the convergence angle. Next, tilt-series acquisitions were
85 applied to a model sample in which PtPd nanoparticles were deposited on a Si pillar placed
86 between a pair of SiN membranes. Here, the field resolution was evaluated using the tilt-
87 averaged standard deviation of the CoM of the membrane-only region, and the spatial
88 resolution was evaluated using the Young's fringe technique with a pair of partially averaged

89 images [19].

90

91 **Experimental**

92 An aberration-corrected microscope (JEOL JEM-ARM200F) equipped with a high-speed

93 pixelated STEM detector (JEOL 4DCanvas) was used at 200 kV for DPC measurement.

94 Convergence semi-angles of 4 mrad and 22.5 μ rad were used, which corresponded to the

95 objective lens ON and OFF conditions, respectively, for measuring the relationship between

96 dose and phase resolution. To maximize the angular resolution, each diffraction pattern was

97 obtained with a maximum of 264×264 pixels, and the CoM at each scan point was calculated

98 from these patterns. The camera lengths were adjusted such that the size of the transmitted

99 disk (Ronchigram) was approximately 70% of the detector's field of view. Prior to data

100 acquisition, the deflector balance for the parallel-beam scan and intermediate lens focus was

101 carefully adjusted such that the Ronchigram did not move along with the scan. For the

102 evaluation of the relationship between electron dose and standard deviations, the experiments

103 were conducted in a vacuum region without any sample. For the model sample measurement,

104 only the 4-mrad convergence semi-angle was used, because the structure was too small for a

105 smaller convergence angle. The 4-mrad convergence semi-angle was selected considering the

106 balance between the spatial and phase resolutions, along with the size of the model structure.

107 The model structure, which imitated environmental cells, was fabricated on a selectively

108 etched Si window-supported SiN (50 nm thick) film as a lower membrane. A Si pillar was
109 placed over it, fabricated using a focused ion beam (FIB), and the upper membrane was
110 placed on top of the Si pillar, sliced from another area of the grid by the FIB. A schematic and
111 transmission electron microscopy (TEM) images are shown in Figs. 1(a) and (b), respectively.
112 To separate the films homogeneously around the pillar, a square wall was created via C
113 deposition before placing the upper membrane. The distance between the films and the height
114 of the edge of the Si pillar were measured via TEM by using the Fourier transform of
115 amorphous membrane contrast (diffractogram), and the inter-membrane and pillar–membrane
116 distances were 2.6 and 1.3 μm , respectively. The Si pillar was coated with PtPd nanoparticles
117 that imitated catalytic particles, and these particles were used as markers for tilt-series image
118 alignment.

119 **[Insert Figure 1 here]**

120 Tilt-series acquisitions were performed using originally developed acquisition software,
121 which controls the microscope deflectors and aperture positions. It controls the aperture
122 positions to pre-specified positions to tilt the incident direction and moves the transmitted
123 beam to the detector position by controlling the deflector after the sample. Six sets of data
124 were acquired consisting of 10 tilt directions with 1.6-mrad steps with the pillar placed
125 between the membranes as the pivot point. A 264×264 pixel diffraction pattern was acquired
126 for each of the 128×128 scan points. The tilt direction was parallel to the edge of the Si

127 pillar. These steps and angles were selected so that the aperture positions were well within the
128 corrected region of the Ronchigram, which was approximately 24 mrad.

129

130 **Results**

131 **Relationship between phase resolution and dose**

132 To determine the achievable phase resolution, the relationship between the dose and the
133 standard deviation of the CoM was evaluated. As stated previously, the phase resolution
134 depends only on the electron dose and the convergence semi-angle of the probe. However,
135 because the probe is scanned, the position of the transmitted disk is affected by the parallelism
136 of the beam and a slight deviation of the detector from the back focal position. Considering
137 the expected resolution of each convergence semi-angle, the data were acquired at
138 magnifications of 4M and 8M for 4 mrad and 200k for 22.5 μ rad, with 128×128 scan points.
139 The results are summarized in Fig. 2.

140 **[Insert Figure 2 here]**

141 To clearly observe the effect of the scan width, the standard deviations derived from the data
142 were separately plotted for the entire scan area, center 1/4 area, and center 1/8 area. The solid
143 blue and orange lines in Fig. 2 correspond to the theoretical predictions (Eq. (2)). Considering
144 that the lines indicate the theoretical lower limit of the resolution, it can be concluded that the
145 result agrees well with the prediction. For the 4-mrad convergence semi-angle, because the

146 magnification is high and the phase resolution is low, the phase resolution does not strongly
147 depend on the magnification or the scan area. Panel (b) presents a magnified image of the
148 enclosed area in (a), which shows that it indeed depends on the scan area but is almost
149 negligible. The green and red horizontal dotted lines represent the standard-deviation values
150 that correspond to $2\pi/100$ rad, assuming a diffraction-limited resolution of 0.38 nm. The
151 plot indicates that $2\pi/100$ rad can be attained using an electron dose of >1000 ($e^-/\text{pattern}$).
152 For the smaller convergence semi-angle of $22.5 \mu\text{m}$, the effect of the scan is obvious. This is
153 due to the (two orders of magnitude) higher phase resolution, and the wider scan is due to the
154 low magnification of 200k. A phase resolution better than $2\pi/100$ rad is still achievable
155 using more than 1000 $e^-/\text{patterns}$; however, resolution improvements along the dose are
156 hindered by the effect of the scan. When the scan area was narrowed to 1/4 and 1/8, the plot
157 approached the theoretical limit. However, the 1/8 scan area corresponds to a magnification of
158 1.6 M, in which the field of view is approximately 130 nm. Because the expected spatial
159 resolution of $22.5 \mu\text{rad}$ is approximately 68 nm, using such a high magnification is not so
160 useful in practice. However, because the parallelism of the scan is reproducible under the
161 same scan conditions, the effect can be compensated for using reference data obtained without
162 a sample.

163

164 **Resolution improvements via tilt-series acquisition for model sample**

165 To improve the resolution of the environmental cell phase measurement, tilt-series acquisition
166 was performed for the model sample, as shown in Fig. 1. According to the results discussed in
167 the previous section, the electron currents were adjusted to approximately 4000 e⁻/pattern on
168 average in the membrane-only region; thus, each pattern in the tilt series was expected to have
169 a base resolution better than $2\pi/100$ rad.

170 The membrane is amorphous in structure and is observed as a granular contrast, and since the
171 tilt angles are still very small, the granular contrast of the films does not change much.

172 However, because the upper and lower membranes are far from the pivot point, tilting around
173 a Pt particle as a pivot results in a significant relative shift in opposite directions. After
174 aligning the tilt series images with the Pt particles and superimposing them, the membrane
175 images overlap with shifted granular contrast images, resulting in an overall reduction in
176 contrast. On the other hand, by correcting the positions of the obtained images with pillar
177 region and summing them, the random noise components present in each image of the tilt
178 series are averaged and thus reduced, which improves contrast. Additionally, summing
179 multiple images is equivalent to effectively increasing the dose. Therefore, averaging the
180 images after aligning the position with the PtPd particles on the pillar blurred the image from
181 the membrane while improving the signal from the pillar.

182 Fig. 3 shows examples of the (a) first and (b) last images of a tilt series and (c) the image after
183 averaging. Averaging was performed after aligning the tilt-series images by using the PtPd

184 particles on the Si pillar as position markers. The upper half of the image corresponds to the
185 pillar region, and the lower half corresponds to vacuum (only membranes). The standard
186 deviation in the lower region (only membranes) before averaging in (a) is 0.07 mrad. As
187 shown in (c), after tilt-series averaging, the smoothing effect in the membrane region is
188 evident, where the granular contrast of the membranes observed in (a) and (b) is almost
189 completely eliminated, while the PtPd particle contrast is improved. The membrane contrasts
190 also overlapped in the pillar region, but these contrasts moved far more upon tilting relative to
191 the PtPd contrast on the pillar; thus, they were effectively smoothed by the averaging
192 procedure. The standard-deviation value for the membrane region after averaging is improved
193 to 0.03 mrad in (c).

194 **[Insert Figure 3 here]**

195

196 **Spatial-resolution- evaluation of tilt-series averaged image**

197 To evaluate the phase precision attainable via DPC, it is necessary to measure not only the
198 standard deviation of the CoM but also the spatial resolution. Young's fringe resolution
199 evaluation [18] was performed to evaluate the spatial resolution of the DPC images after tilt-
200 series averaging. Regarding the photographs in the tilt-series datasets, the first half were
201 aligned with the first image, and the remaining half were aligned with the last image, resulting
202 in pairs of averaged images with slight shifts relative to each other. These pairs of images

203 were superimposed and used for the Young's fringe evaluation. Fig. 4 presents example
204 images for the CoM of the x direction (a, b), and the CoM of the y direction (d, e). The spatial
205 resolution was evaluated as 0.79 nm for this case. Here, the x and y directions correspond to
206 the directions of the detector, and because they are rotated approximately 45 degrees from the
207 direction of the sample edge on the diffraction plane, edge contrast appears in both the CoM_x
208 and CoM_y images.

209 The resolution evaluation results using just two images (the first and last) were shown in Fig.
210 4 (c) and (f) for CoM_x, and CoM_y respectively. In comparison to the evaluations performed
211 after aligning and summing five images shown in Fig. 4(b) and (e), the Young's fringe images
212 created with just two images exhibit poorer contrast. Specifically, there is a slight degradation
213 in the x direction and a more pronounced degradation in the y direction. This indicates that,
214 due to the small tilt angle increment of 1.6 mrad and a total tilt of only 16 mrad which is well
215 within the aberration corrected phase flat area of around 15 mrad (semi-angle), the changes of
216 the aberrations between individual images are minimal when acquiring the tilt series.
217 Consequently, the improvement in the signal-to-noise ratio from summing the images leads to
218 an overall enhancement in resolution, outweighing any degradation in resolution from
219 overlaying different images.

220 **[Insert Figure 4 here]**

221 The evaluated spatial resolutions for all the datasets are presented in Fig. 5, together with the

222 standard deviation of the CoM of the vacuum (membranes only) regions (lower part of the
223 tilt-series averaged image). As indicated by Eq. (1), the achievable phase resolution can be
224 determined using a pair of spatial resolutions and the standard deviations of the CoM. The
225 dotted line indicates the boundary below which the resolution of $2\pi/100$ rad is achieved. As
226 shown, most of the datasets are well within the range, suggesting that the phase resolution of
227 $2\pi/100$ rad can be achieved using the proposed tilt-series acquisition method by minimizing
228 the film contrast for the sample in an environmental cell.

229 **[Insert Figure 5 here]**

230

231 **Discussion**

232 Here, we discuss the comparison between the proposed method and the method of using a
233 large convergence angle to improve depth resolution. Assuming the angle range typically
234 correctable by an aberration corrector is 30 mrad, the depth obtained as the FWHM (Full
235 Width at Half Maximum) of the probe intensity is $\Delta z = 1.77 \lambda/\alpha^2$, which is approximately 5
236 nm, providing sufficient resolution to clearly resolve the center of the environmental cell.
237 Furthermore, with a convergence angle of 30 mrad, the probe spread at the position of the
238 membrane, which is $1.3 \mu\text{m}$ away from the focal point, is $1.3 \mu\text{m} \times 0.03 \text{ rad} = 39 \text{ nm}$ in
239 radius, or 78 nm in diameter. This means that the influence of the amorphous structure within
240 this range will be averaged out, thus significantly reducing the membrane contrast. However,

241 increasing the convergence angle in DPC reduces the resolution of the detected deflection
242 angle changes. As shown by Equation (2), when the dose is kept constant, the standard
243 deviation increases proportionally with the convergence angle making it difficult to detect
244 small deflection angles, such as those caused by the potential distributions around catalyst
245 nanoparticles. Therefore, it is necessary to choose an appropriate convergence angle
246 according to the target to be measured. On the contrary, reducing the influence of the
247 membrane by acquiring a tilt series can be done independently of the choice of convergence
248 angle, allowing the convergence angle to be freely chosen according to the target of
249 observation.

250 **Conclusion**

251 A simple technique to improve the resolution of the phase measurement of DPC for
252 environmental cell applications was developed and tested using a model sample simulating
253 environmental cell observations. The relationship between the dose and the attainable CoM
254 precision was tested for two convergent semi-angles that coincided well with theoretical
255 predictions. The pairs of spatial resolutions and standard deviation of the CoM were evaluated
256 for the images obtained via tilt-series acquisition, and the results indicated that $2\pi/100$ rad is
257 well achievable using the proposed tilt-series acquisition method for the sample in an
258 environmental cell.

259

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263

264 **Conflict of interest**

265 The authors declare that they have no conflict of interest.

266

267 **Acknowledgement**

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269

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309 **Figure Legends**

310 **Fig. 1** (a) Schematic of the model sample structure and tilt-series acquisition; (b) TEM image
311 of a model sample.

312 **Fig. 2** (a) Relationship between the electron dose and the standard deviation of the CoM for
313 convergence semi-angles of 4 mrad and 22.5 μ rad. (b) Magnified image of the enclosed
314 region in (a). The solid lines represent theoretical predictions, and the dotted lines represent
315 standard deviations that correspond to the phase precision of $2\pi/100$ rad, assuming
316 diffraction-limited spatial resolutions.

317 **Fig. 3** Example images of tilt-series acquisition of the Si pillar edge region of the model
318 sample. The upper half of the image corresponds to the pillar region, and the lower half of the
319 image corresponds to the vacuum (only membranes). (a) First and (b) last images of a tilt-
320 series and (c) the image after averaging. The averaging was performed after aligning tilt-
321 series images by using PtPd particles on the Si pillar as position markers.

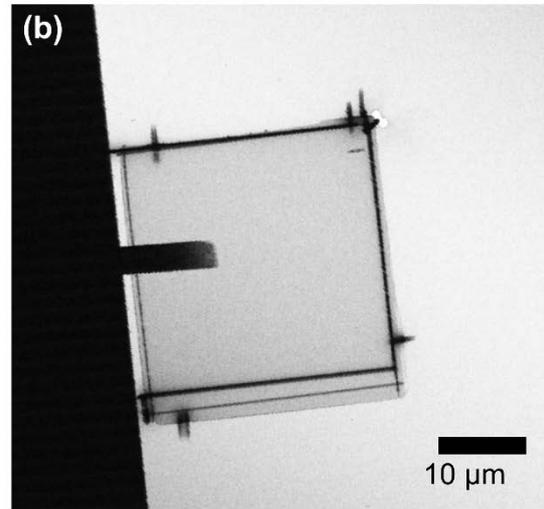
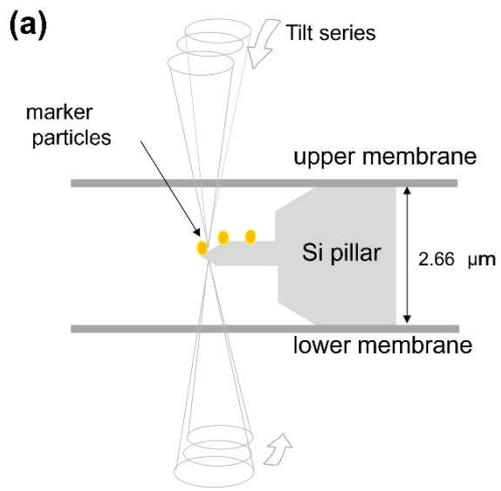
322 **Fig. 4** Example images for Young's fringe spatial resolution evaluation of tilt-series
323 acquisition of the Si pillar edge region of the model sample. Regarding the photographs in tilt-
324 series datasets, the first half were aligned with the first image, and the remaining half were
325 aligned with the last image. The resultant pair of images were superimposed and used for

326 Young's fringe evaluation. (a) Resultant averaged image of CoM_x; (b) Fourier transform of
327 (a); (d) CoM_y; (f) Fourier transform of (d). (c) and (f) are the Young's fringe evaluation result
328 using just two images (the first and last) for CoM_x, and CoM_y, respectively.

329 **Fig. 5** Plot of the spatial resolution versus the standard deviation of the CoM, showing the
330 achievable phase resolution. The dotted line indicates the boundary below which the
331 resolution of $2\pi/100$ rad is achieved.

332

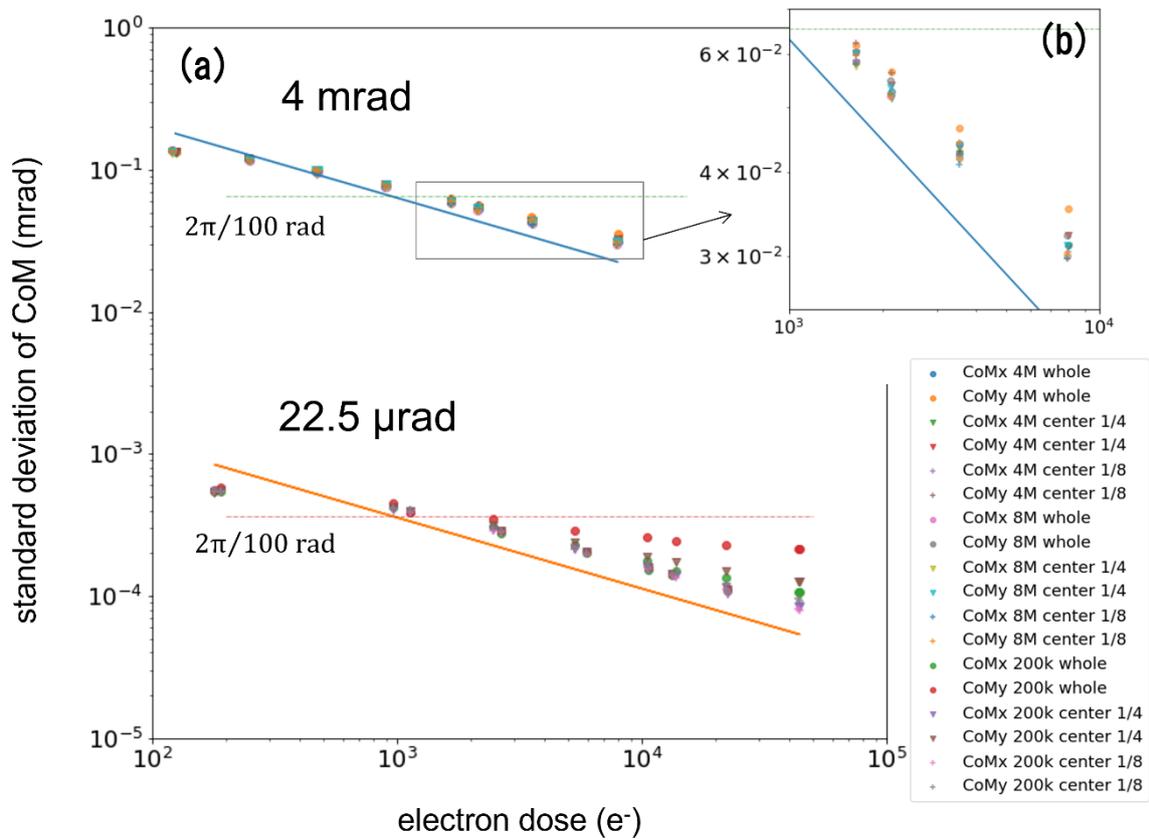
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335 Figure 1

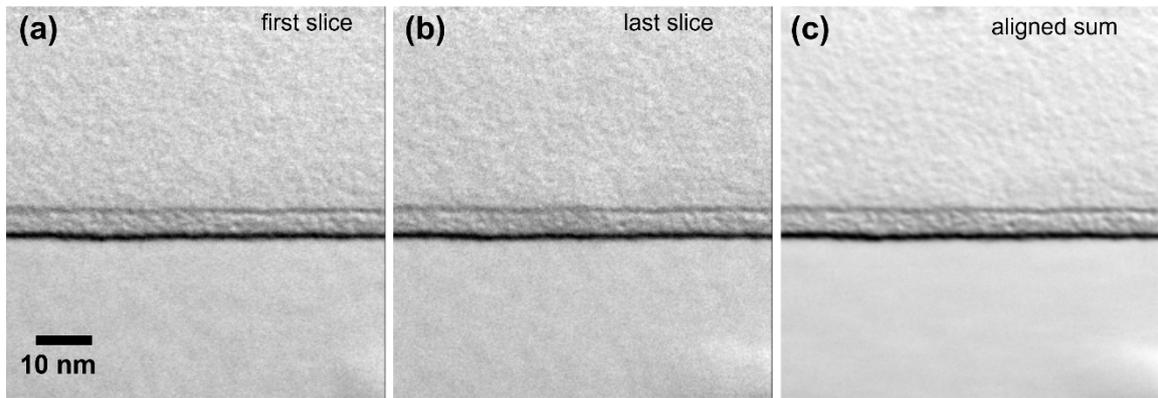
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338 Figure 2

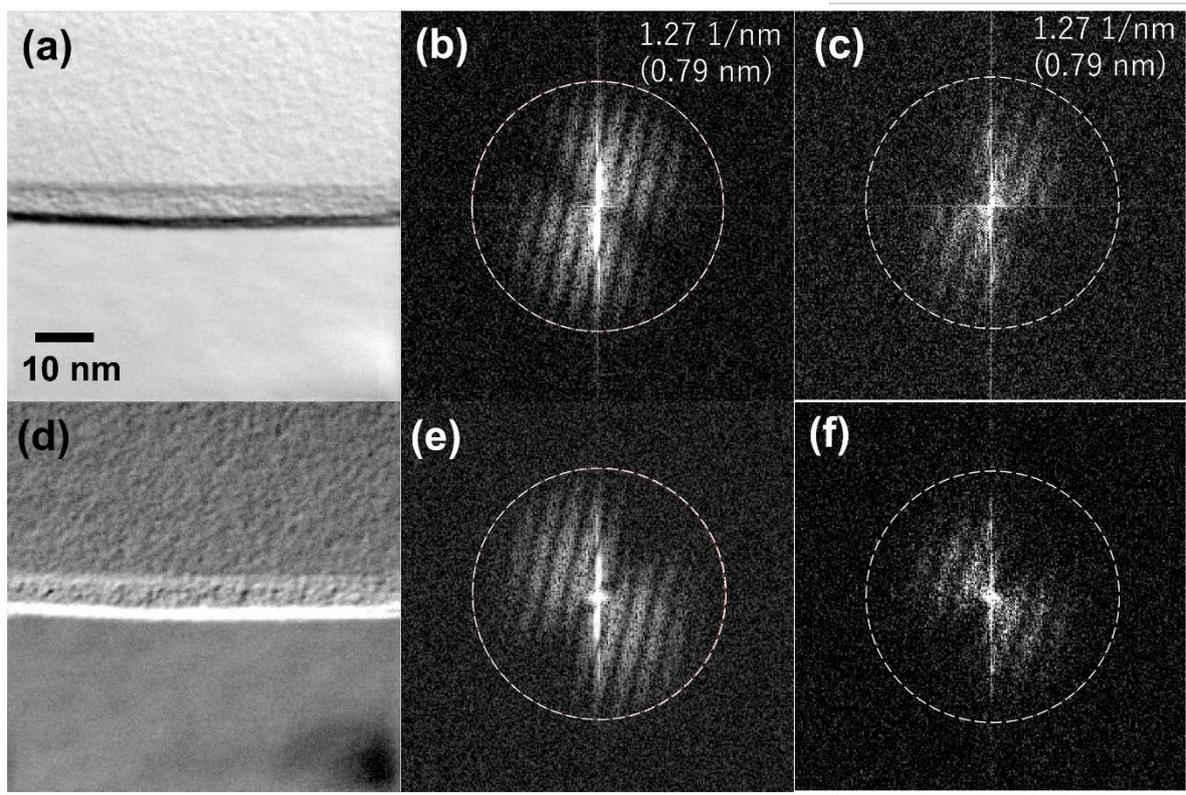
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341 Figure 3

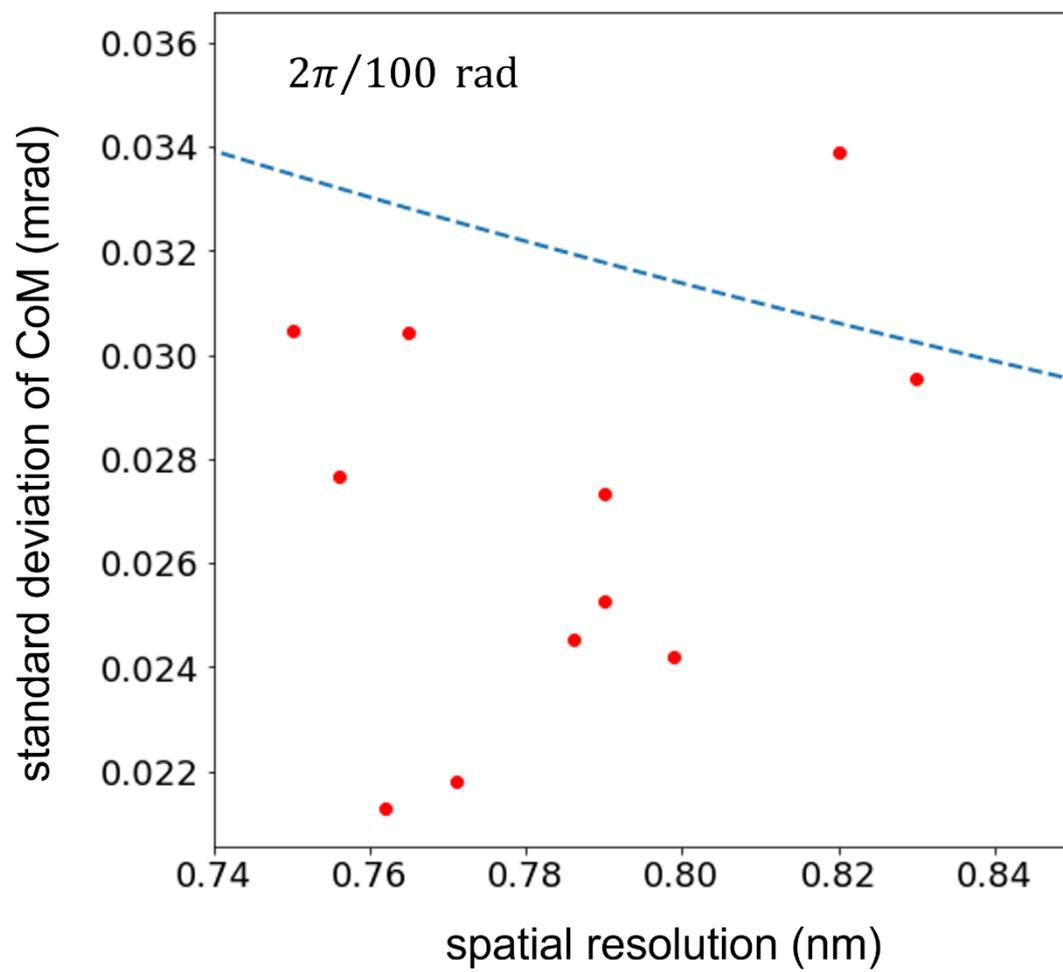
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344 Figure 4

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347 Figure 5